Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/673,564	LEE, SEUNG SIN
Examiner	Art Unit
Anabel M. Ton	2875

SEARCHED				
Class	Subclass	Date	Examiner	
362	494	8/5/2005	AT	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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